

Notice of References Cited	Application/Control No. 10/074,265	Applicant(s)/Patent Under Reexamination PAVEY, NICHOLAS	
	Examiner Hugh Jones	Art Unit 2128	Page 1 of 1

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	D	US-6,694,497	02-2004	Pavey, Nicholas	716/4
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	M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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